AMENDMENTS TO THE SPECIFICATION

Please rewrite the paragraph beginning on Page 8, line 6 as follows:

--Next, in step S2, it is determined whether or not Monte Carlo analysis of the circuit characteristic of the semiconductor device is appropriate. If possible, the Monte Carlo analysis on the circuit characteristic in step S3 is carried out. The ~~is a~~ criterion for determination is that time required for Monte Carlo analysis on the circuit characteristic should not be too long. More specifically, the circuit size of the FET or the like composing the circuit acts as the criterion for determination. In step 3, the Monte Carlo analysis of the circuit characteristics, and in step S4, the Monte Carlo analysis of process fluctuation on individual devices such as the FETs composing the circuit are carried out. In step S4, the Monte Carlo analysis of the process fluctuation is carried out in the Monte Carlo analyzing unit 2 for process fluctuation shown in Fig. 5. In this analysis, the fluctuation of the circuit characteristic is obtained, and then the simulation method is complete.—

Please rewrite the paragraph beginning on Page 8, line 21 as follows:

--In step S5, the worst-case analysis of the process fluctuation with K-value as a variable is carried out on devices by the worst case analyzing unit 3 for process fluctuation corresponding to arbitrary K value of Fig. 5. The circuit of the semiconductor uses plural devices such as the FETs. Because only the same result can be obtained even if process fluctuation analysis is carried out for the same structure device, the analysis is carried out once for each different structure. For example, if the nFETs and ~~nFETs~~ pFETs in the circuit are all of the same structure, the analysis on the nFET and pFET only has to be carried out once for each.—

Please rewrite the paragraph beginning on Page 13, line 23 as follows:

--In step S8 of Fig. 6, the processing step ~~another~~ advances by the worst-case analysis of the circuit characteristics of Fig. 5 being carried out by the worst-case analyzing unit 5, so as to obtain a fluctuation 25 in the circuit characteristics. This analysis result is

recorded in the fluctuation width recording unit 9. In this case, using the "σvalue after optimization" already obtained from the fluctuation analysis of the device characteristic, the fluctuation 25 of the circuit characteristic of a large scale circuit can be estimated quickly at high accuracy.--